

PCI Express Card Edge Connector, Straddle Mount Type

1. SCOPE

1.1. Contents

This specification covers the performance, tests and quality requirements for the Tyco Electronics PCI Express Card Edge connector, Straddle Mount Type.

1.2. Qualification

When tests are performed on the subject product line, the procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

2. APPLICABLE DOCUMENT

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. TE Electronics Documents

- 109-1: General Requirements for Test Specifications
- 109-197: Test Specification (AMP test Specifications vs EIA and IEC Test Methods)
- TEC-109-201: Component Heat Resistance to Lead-Free Reflow Soldering.
- 501-57885 : Test Report (Part numbers are as shown in Appendix. 1)

2.2. Industry Standard

- EIA-364: Electrical Connector/Socket Test Procedures Including Environmental Classifications.
- JESD22-B102D: Solderability Test Method.
- PCI Express Card Electromechanical Specification

3. REQUIREMENTS

3.1. Design and Construction

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2. Materials

Materials used in the construction of product shall be as specified on the applicable product drawing.

3.3. Ratings

Voltage : 50 VAC rms Current: 1.1 A Max.

Temperature : - 40°C to 85°C

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3.4. Performance and Test description

The product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions per EIA-364.

3.5. Test Requirements and Procedures Summary

TEST ITEM		REQUIREMENT	PROCEDURE				
1	Examination of Product	Meets requirements of product drawing. No physical damage.	Visual inspection.				
	ELECTRICAL REQUIREMENT						
2	Low Level Contact Resistance	30 mΩ Max. (Initial) 30 mΩ Max. (Final)	Subject mated contacts assembled in housing. Open circuit at 20mV Max, 100mA Max.				
			EIA-364-23B, Figure-3				
	Dielectric Withstanding Voltage	No creeping discharge or flashover	500 VAC for 1minute				
3		shall occur.	Test between adjacent circuits of unmated connector.				
		Current leakage: 0.5 mA Max.	EIA-364-20B, Method B, Condition II				
	Insulation Resistance		Impressed voltage 500 VDC.				
4		1,000 MΩ Min. (Initial) 1,000 MΩ Min. (Final)	Test between adjacent contacts of unmated connector for 1 minutes.				
		` '	EIA-364-21C.				
	Temperature rise.		The sample size is a minimum of three mated connectors.				
			The sample shall be soldered on a PC				
			board with the appropriate footprint.				
5		1.1 A per pin minimum. The temperature rise above ambient shall not exceed 30°C. The ambient condition is still air at 25°C.	Wire the eight power pins (B1, B2, B3, A2, A3, B8, A9, and A10) and the eight nearest ground pins (A4, B4, B7, A12, B13, A15, B16, and B18) in a series circuit. The mated add-in card is included in this circuit. The add-in card shall have 1 oz. copper traces and its mating geometry shall conform to the applicable PCI Express drawings.				
		u. 20 0.	A thermocouple of 30 AWG or less shall be placed on the card edge finger pad (pins B) and A9) as close to the mating contact as possible.				
			Conduct a temperature rise vs. current test.				
			EIA-364-70, Method 2				

Figure 1 (Continue)

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TEST ITEM		REQUIREMENT	PROCEDURE				
MECHANICAL REQUIREMENT							
6	Mating Force (Add-In Card)		Operation Speed: 12.5 mm/min. Max.				
		117g per centeet peir mevimum	Measure the force required to mate connector.				
		117g per contact pair maximum.	Using a steel gauge 1.70+0.00/-0.01 mm thickness.				
			EIA-364-13B				
	Un-mating Force (Add-In Card)		Operation Speed: 12.5 mm/min.Max.				
7		15g per contact pair minimum.	Measure the force required to unmate connector.				
'		13g per contact pair minimum.	Using a steel gauge 1.44+0.01/-0.00 mm thickness.				
			EIA-364-13B				
			Operation Speed: 200 cycle/hour Max.				
8	Durability	[See Note 1]	Number of cycles: 200 cycles				
			EIA-364-09C				
9	Reseating.	See NOTE	Manually unplug/plug the connector. Perform 3 such cycles.				
			Subject mated connectors.				
	Vibration (random)		Vibration Frequency : 10 - 2,000 Hz (random)				
		No electrical discontinuity greater	Accelerate Velocity: 30.38 m/s2 (3.1G)				
10		than 1µ sec shall occur.	Vibration Duration: 15 min				
		[See Note 1]	Vibration Direction: In each of 3 mutually perpendicular planes.				
			.EIA-364-28D, Test Condition VII, Tester Legger D				
	Mating force (PCB)		Operation Speed: 12.5 mm/min. Max.				
11		120g per contact pair maximum.	Measure the force required to mate connector.				
			Using a PCB 1.80±0.1 mm thickness				
			EIA-364-13B				
	Unmating force (PCB)		Operation Speed: 12.5 mm/min.Max.				
12		30g per contact pair minimum.	Measure the force required to unmate connector.				
			Using a PCB 1.80±0.1 mm thickness.				
			EIA-364-13B				

Figure 1 (Continue)

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13 \$		REQUIREMENT	PROCEDURE				
	TEST ITEM Solderability	The inspected area of each lead must	Steam Aging Preconditioning: Intended for tin and tin-alloy leadfinishes for				
		have 95% solder coverage minimum.	Solder pot temperature: 245±5℃, 5sec.				
			JESD22-B102D, Condition C				
	ENVIRONMENTAL REQUIREMENT						
			Moisture Soak precondition $: 85^{\circ}\mathbb{C}, 85^{\circ}\mathbb{RH}$ for 168 hours.				
			Pre Heat : 150~200°C, 60~180sec.				
			Peak Temp. : 260+0/-5°C, 20~40sec.				
	Resistance to Reflow		Ramp to peak ∶ 3°C max. per second				
		No physical damage shall occur.	Ramp to cool down ∶ 6°ℂ max. per second				
	See Note 2]		Time over liquids (217°ℂ) :60~150 sec				
			Duration: 3 cycles				
			TE spec. 109-201, Test condition B,				
			Refer to Figure 4.				
			Mated Connector				
15 7	Thermal Shock	[See Note 1]	-55+0/-3℃ (30 min.), +85+3/-0℃ (30 min.)				
15			Perform this cycle, repeat 10 cycles				
			EIA-364-32C, Method A, Test condition I				
	Humidity Temperature Cycling		Mated Connector				
			25 $^{\circ}$ C to 65 $^{\circ}$ C, 90% to 95% RH.				
In		[See Note 1]	Perform this cycle, repeat 10 cycles (10days)				
			EIA-364-31B, Method III, Condition B,				
-	Temperature Life		Mated Connector, 105 $^\circ\!$				
17	(Heat Aging)	[See Note 1]	EIA-364-17B, Method A, Test condition 4 (w/o electrical load),				
			Mated Connector, 105 $^\circ\!$				
18	Temperature life	See NOTE	EIA-364-17B, Method A, Test condition 4				
	(Preconditioning).		(w/o electrical load),				
16 5	Salt Spray	contact area and base metal exposed.	Subject mated connectors to 35+/-2 °C and 5+/-1% salt condition for 48hours. After test, rinse the sample with water and recondition the room temperature for 1 hour. EIA-364-26B				

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Figure 1 (End)



- Note 1 : Shall meet visual requirements, show no physical damage, and meet requirement of additional tests as specified in the test sequence in Figure 2
- Note 2 : Resistance to soldering process is indicated on notes of customer drawing. Select the appropriate test type which drawing notes are matched with.

3.6. Product Qualification and Requalification test

	Test Group								
Test or Examination	Α	В	С	D	Е	F	G	Н	- 1
	Test Sequence (a)								
Examination of product	1, 9	1, 8	1, 10	1, 8	1, 8	1, 3	1, 3	1, 3	1,4
Low level contact resistance	3, 7	2, 5, 7	2, 5, 7, 9	2, 5, 7					
Dielectric withstanding voltage					2, 6				
Insulation resistance					3, 7				
Temperature rise								2	
Mating force (Add-In Card)	2, 6								
Unmating force (Add-In Card)	4, 8								
Durability	5	3	3	3					
Reseating		6	8						
Vibration (random)				6					
Mating force (PCB)									2
Unmating force (PCB)									3
Solderability						2			
Resistance to Reflow soldering heat							2		
Thermal shock			4		4				
Humidity-temperature cycling.			6		5				
Temperature life		4							
Temperature life (Preconditioning)				4					

NOTE: (a) Numbers indicate sequence in which tests are performed.

(b) Discontinuities shall not take place in this test group, during tests.

Figure 2

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Figure 3. Low Level Contact Resistance

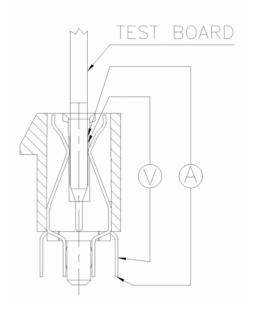


Figure 4. Temperature Profile of Reflow Soldering



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单击下面可查看定价,库存,交付和生命周期等信息

>>TE Connectivity(泰科)